

IEEE Standard for the Testing of Overhead Transmission and Distribution Line Hardware

Sponsor

**Transmission and Distribution Committee
of the
IEEE Power Engineering Society**

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Abstract: Requirements for mechanically testing load-rated line hardware for use on transmission and distribution facilities are described. Items specifically addressed in this standard include clevis and eye fittings, Y-clevis fittings, socket fittings, ball fittings, chain links, shackles, triangular and rectangular yoke plates, suspension clamps, and strain clamps. This standard is intended to cover routine acceptance testing. It is not intended for initial design tests.

Keywords: acceptance testing, load-rated line hardware

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Introduction

(This introduction is not part of IEEE Std C135.61-1997, IEEE Standard for the Testing of Overhead Transmission and Distribution Line Hardware.)

This standard covers the requirements for the testing and acceptance of transmission and distribution line hardware. The standard covers routine acceptance testing, and is not intended for use for initial design tests.

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